

Latch-Type Sense Amplifier Modification for Coupling Suppression

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Abstract

When continuously increase the semiconductor fabrication technology, then continually shrink the channel length and pitch of the CMOS device with the vigorous process variation and signal coupling effect. Here explained how the action of sense amplifier disturbed by the property of coupling effect. In this paper, we design the single stage amplifier, modified single stage amplifier and multistage amplifier. The operational amplifier contains the high gain, high input impedance and low output impedance. The circuits are simulated by using the .25 μ m CMOS technology. All results obtained by using the tanner tool version 13.0 software. The comparison among all amplifiers parameters like as power dissipation, leakage voltage and supply voltage of the circuit.

Keywords Operational Amplifier (OP-AMP), CMOS, Metal oxide semiconductor (MOS)

I. INTRODUCTION

It is essential for all memories as that dynamic random access memory (DRAM) and static random access memory (SRAM) for any read, write operations. It shows the comparison between bit line voltage and rail to rail complemented output voltage. It sense mainly write operation [1]. It is a peripheral circuit which are exist in each and every column of memory array. It detects the correct signal when the input difference voltage of the sense amplifier is larger than off-set voltage of the sense amplifier and amplifier gives the correct logic levels. Ideally the off-set voltage of any sense amplifier is approximately zero but practically it is not possible because due to the devices or transistors mismatching [4]. When the off-set voltage of sense amplifier is approximately zero then the sense amplifier sense the correct voltage which are present in the input bit lines whenever the differential bit line voltage does not zero.

We discuss the when introducing the coupling capacitance in sense amplifier then the sense amplifier how to act due to the coupling effect [2]. Here we control the time by using the output waveform's transient and Fourier analysis. We can achieve the enhancement CMOS structure under the differential input in our tanner tool spice design and this can implemented by the use of .25 μ m CMOS technology. The sense amplifier's basic process is to sense the

differential input voltage and to reduce the dynamic dissipated power and access time of sense amplifier [5]. This is more capable to differential noises and offset voltages and by using the output waveform we check the coupling effect in sense amplifier when comparison with the old CMOS design.

In analog electronics the most important and useful component is operational amplifier. The operational amplifier used most widely in electronics but it contains some limitation which performance depends upon operating frequency which is not exceeding the 1Mz. Some models have been designed for higher operating frequency [10].

II. PREVIOUS WORK

A. Couple Suppress Sense Amplifier (CSSA)

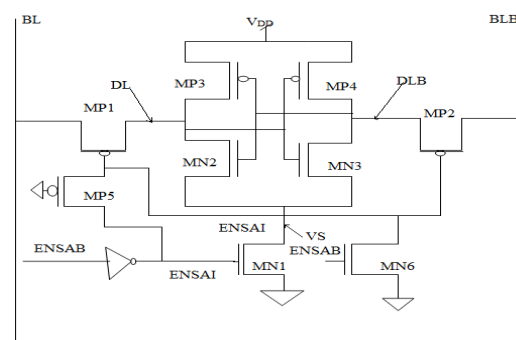


Figure 1: CMOS Representation of CSSA

In couple suppress sense amplifier two devices extra added in this circuit. The one device is MP5 which is connected in between the ENSAI and the two transistors gate terminals which are MP1 and MP2. The transistor MP5 always turned ON [1]. When we give the logic high on the ENSAI then the ENSAI will not rise until the value of ENSAI goes the threshold voltage or below the threshold voltage of the transistors MP5. Due to this the transistors MP1 and MP2 go to switched OFF after than the VS drop and the other device which is NMOS which name MN6 is the second device [7]. The second device MN6 act as driver, which drive to ENSAI to the ground when the sense amplifier not in working condition. The two extra added devices have very small size like as MP5 and MN6 transistors, which contain very small delay between ENSAI and ENSAI. Then due to the very small size of the extra added

C. Proposed Circuit Diagram of Two Stage Amplifier

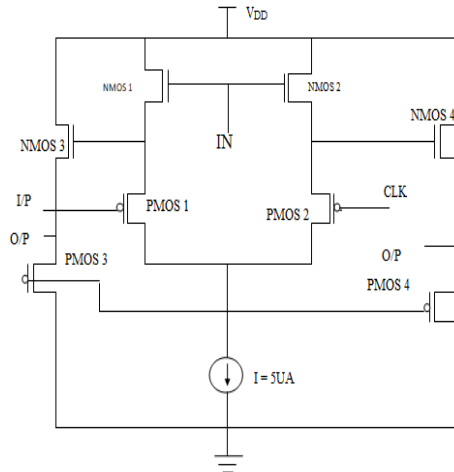


Figure 4 Multistage Amplifier

This is the cascade of two stages, the first stage provides the high gain and second stage provides the large output swing. This circuit contains the 8 transistors and one current source ($I = 5$ micrometer). These 8 transistors name as 4 PMOS transistors and 4NMOS transistors. The input terminal is common for both NMOS1 and NMOS2 gate terminal and inputs I/P and clock pulse provided through the PMOS1 and the PMOS2 transistors. The PMOS transistors PMOS3 and PMOS4 are connected back to back through gate terminals.

The circuit is simulated by using the tanner 13 version software and the output waveform find using this tool and also calculate the dissipated power for each proposed circuit. Take the dimension of each transistors is length $L = .25$ micrometer and width of each transistors is $W = 2.5$ micrometer. In this circuit the output is taken in between PMOS3 and NMOS3 source terminals.

III. SIMULATED RESULT

A. Schematic Diagram of Single Stage Amplifier

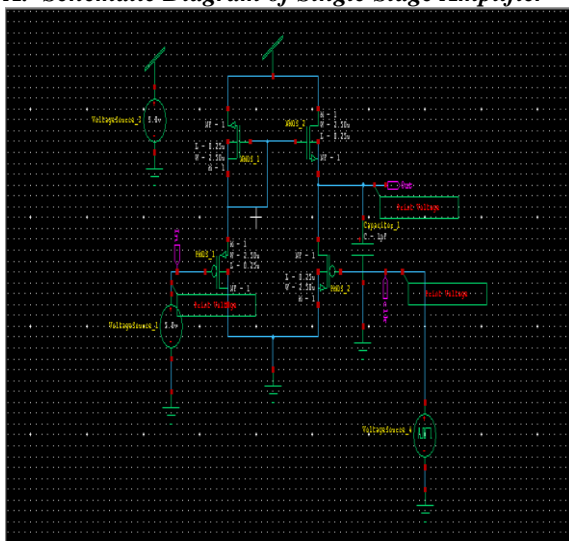


Figure 5 Schematic Diagram of III (A)

B. Output Waveform of Single Stage Amplifier

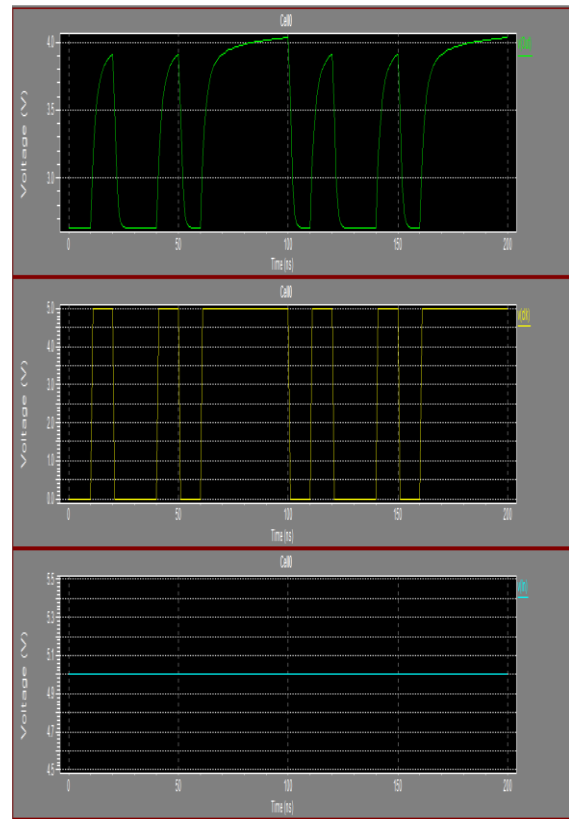


Figure 6 Waveform of III (B)

In this circuit we take a clock pulse which value is 0100101111 (bit value) and input is 5v and output waveform show the amplified charging and discharging due to the capacitance at the output node.

C. Modified Single Stage Amplifier

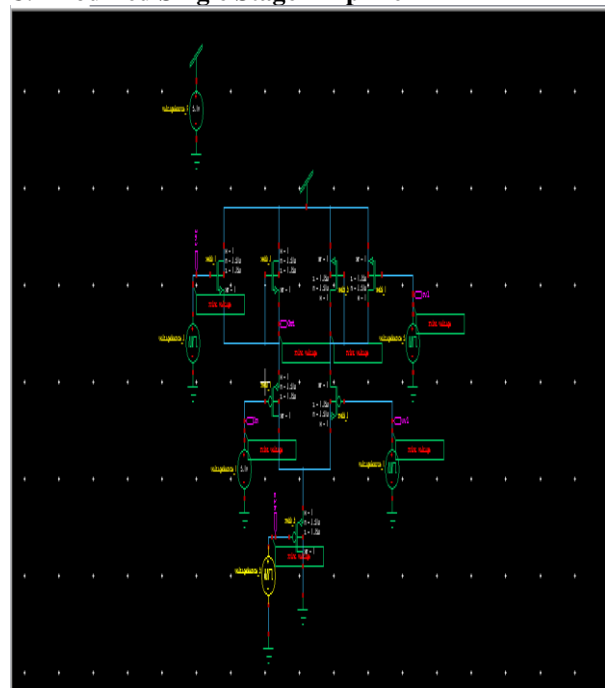


Figure 7 Schematic of III (C)

D. Output Waveform of Modified Single Stage Amplifier

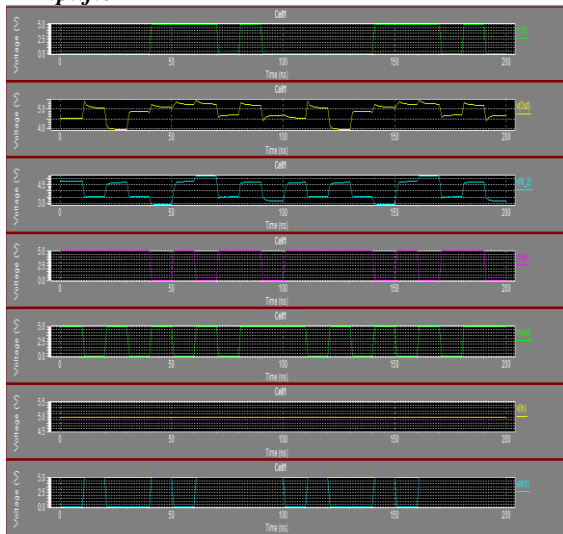


Figure 8 Output Waveform of III (D)

This output waveform show the read and write operation when we apply the input $In = 5.0v$ and clock (0000111010) and $In1 = 01000101111$. The read operation bit contain $rw1 = 1111010110$ and write operation contain the bit $ww1 = 1010101011$ then during this the output voltage amplified and during amplifying some distortion exist in the output and due to this the leakage voltage exist and also reduce the power dissipation.

E. Schematic of Two-Stage Amplifier

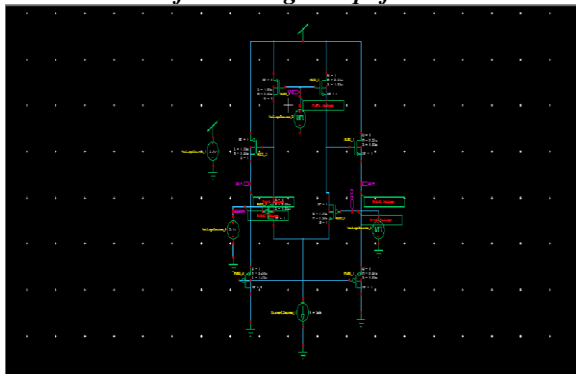


Figure 9 Schematic of III (E)

F. Output Waveform of Two-Stage Amplifier



Figure 10 Output Waveform of III (F)

In two stage, the output waveform show the amplified output voltage during this some distortion exist which is 1.6v. In this the input bit is 0100101111 and clock pulse is 0100101111 and input voltage is 5.0v.

IV. COMARISON TABLE

	Single stage amplifier	Modified single stage amplifier	Two stage amplifier
Supply voltage	5.0V	5.0V	5.0V
Output voltage	4.3V	4.6V	3.4V
Leakage voltage	0.7V	0.4V	1.6V
Power dissipation	1.707×10^{-3} Watts	2.457×10^{-7} Watts	2.237×10^{-13} Watts
technology	0.25 μ m	0.25 μ m	0.25 μ m

V. CONCLUSION

Various types of operational amplifier were designed and these implemented circuits which are single stage amplifier, modified single stage amplifier and two stage amplifier simulated by the tanner simulated tool by using the .25 μ m CMOS technology. The OP-AMP show the leakage voltage, power dissipation, input voltage and output voltage.

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